

Notice of References Cited	Application/Control No. 10/685,322	Applicant(s)/Patent Under Reexamination HIRST ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 01120342 A	05-1989	Japan	KAWAKAMI et al.	B41F 23/04
	O	JP 2004272131 A	09-2004	Japan	IJIMA, YOSHIHIKO	G03G 15/20
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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